



佳恩半导体
JIAENSEMI

JFFC18N65C
JFPC18N65C

650V N-Channel MOSFET

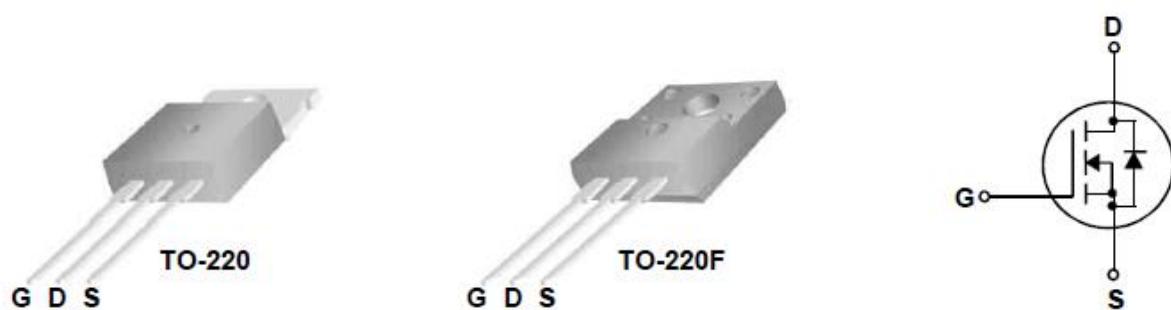
General Description

This Power MOSFET is produced using advanced planar stripe DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode.

These devices are well suited for high efficiency switched mode power supplies, active power factor correction based on half bridge topology.

Features

- 18A, 650V, RDS(on)typ. = 0.45Ω@VGS = 10 V
- Low gate charge(40nC)
- High ruggedness
- Fast switching
- Improved dv/dt capability



Absolute Maximum Ratings $T_c = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	JFPC18N65C	JFFC18N65C	Units
V_{DSS}	Drain – Source Voltage	650		V
I_D	Drain Current Continuous ($T_c = 25^\circ\text{C}$)	18	18*	A
	Continuous ($T_c = 100^\circ\text{C}$)	11.2	11.2*	A
I_{DM}	Drain Current - Pulsed (Note 1)	65		A
V_{GSS}	Gate – Source Voltage	± 30		V
EAS	Single Pulsed Avalanche Energy (Note 2)	245		mJ
I_{AR}	Avalanche Current (Note 1)	18		A
E _{AR}	Repetitive Avalanche Energy (Note 1)	24		mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)	9.8		V/ns
P_D	Power Dissipation ($T_c = 25^\circ\text{C}$)	245	42	W
	-Derate above 25°C	2.0	0.4	W/ $^\circ\text{C}$
T_J, T_{STG}	Operating and Storage Temperature Range	-55 to +150		$^\circ\text{C}$
T_L	Maximum lead temperature for soldering purposes 1/8" from case for 5 seconds	300		$^\circ\text{C}$

*Drain current limited by maximum junction temperature.

Thermal characteristics

Symbol	Parameter	JFPC15N60C	JFFC18N65C	Units
R_{\thetaJC}	Thermal Resistance, Junction-to-Case	0.51	3.0	°C/W
R_{\thetaJS}	Thermal Resistance, Case-to-Sink Typ.	0.46	--	°C/W
R_{\thetaJA}	Thermal Resistance, Junction-to-Ambient	62.5	62.5	°C/W

Electrical Characteristics $T_c = 25^\circ C$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
Off Characteristics						
BV_{DSS}	Drain – Source Breakdown Voltage	$V_{GS} = 0 V, I_D = 250 \mu A$	650	--	--	V
$\Delta BV_{DSS}/\Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu A$, Referenced to $25^\circ C$	--	0.7	--	V/°C
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 650 V, V_{GS} = 0 V$	--	--	10	uA
		$V_{DS} = 520 V, T_c = 125^\circ C$	--	--	100	uA
I_{GSSF}	Gate-Body Leakage Current, Forward	$V_{GS} = 30 V, V_{DS} = 0 V$	--	--	100	nA
I_{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -30 V, V_{DS} = 0 V$	--	--	-100	nA
On Characteristics						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	2.0	--	5.0	V
$R_{DS(on)}$	Static Drain-Source on-Resistance	$V_{GS} = 10 V, I_D = 9 A$	--	0.42	0.50	Ω
g_{FS}	Forward Transconductance	$V_{DS} = 40 V, I_D = 9 A$ (Note 4)	--	19.0	--	S
Dynamic Characteristics						
C_{iss}	Input Capacitance	$V_{DS} = 25 V, V_{GS} = 0 V, f = 1.0 \text{ MHz}$	--	2240	--	pF
C_{oss}	Output Capacitance		--	200	--	pF
C_{rss}	Reverse Transfer Capacitance		--	15	--	pF
Switching Characteristics						
$t_{d(on)}$	Turn-On Delay Time	$V_{DS} = 325 V, I_D = 15.0 A, R_G = 6 \Omega, V_{GS} = 10 V$ (Note 4,5)	--	14	--	ns
t_r	Turn-On Rise Time		--	55	--	ns
$t_{d(off)}$	Turn-Off Delay Time		--	60	--	ns
t_f	Turn-Off Fall Time		--	70	--	ns
Q_g	Total Gate Charge	$V_{DS} = 325 V, I_D = 15.0 A, V_{GS} = 10 V$ (Note 4,5)	--	52	--	nC
Q_{gs}	Gate-Source Charge		--	11	--	nC
Q_{gd}	Gate-Drain Charge		--	18.0	--	nC
Drain – Source Diode Characteristics and Maximum Ratings						
I_S	Maximum Continuous Drain-Source Diode Forward Current	--	--	18	--	A
I_{SM}	Maximum Pulsed Drain-Source Diode Forward Current	--	--	65	--	A
V_{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 V, I_S = 15.0 A$	--	--	1.4	V
t_{rr}	Reverse Recovery Time	$V_{GS} = 0 V, I_S = 15.0 A$ $dI/dt = 100 A/\mu s$ (Note 4)	--	410	--	ns
Q_{rr}	Reverse Recovery Charge		--	2.5	--	uC

Notes:

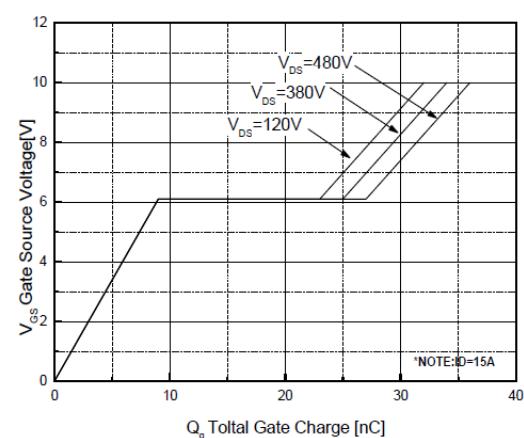
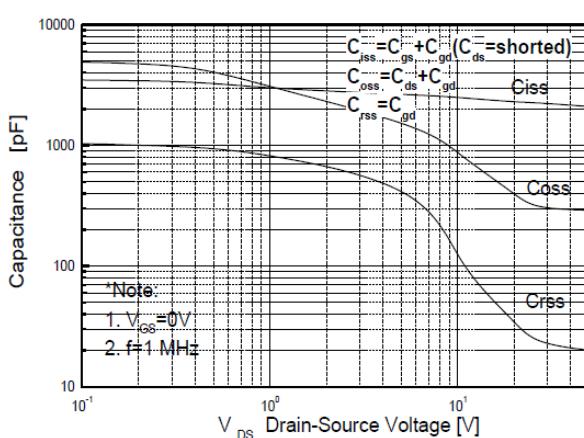
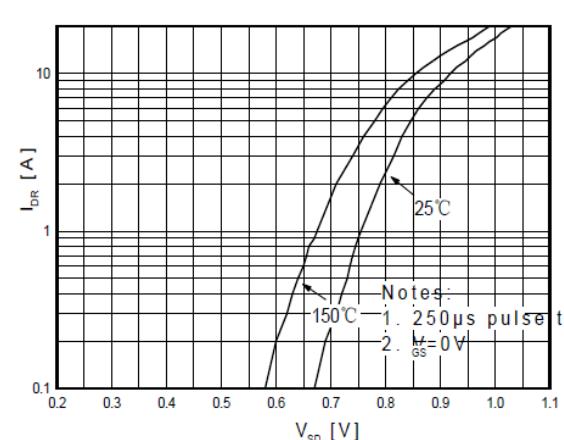
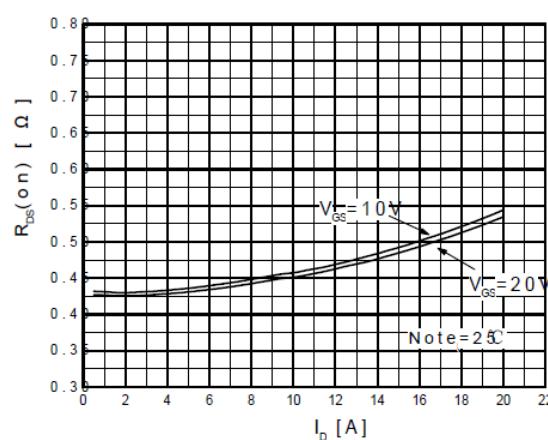
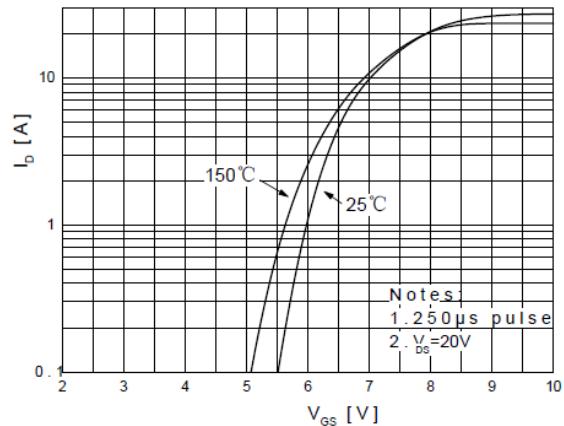
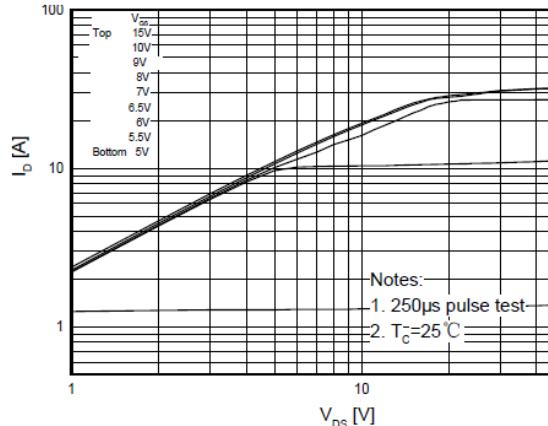
- Repetitive Rating : Pulsed width limited by maximum junction temperature
- $L = 2.0 \text{ mH}$, $I_{AS} = 15 A$, $V_{DD} = 50 V$, $R_G = 25 \Omega$, Starting $T_J = 25^\circ C$
- $I_{SD} \leq 15.0 A$, $di/dt \leq 200 A/\mu s$, $V_{DD} \leq BV_{DSS}$, Starting $T_J = 25^\circ C$
- Pulsed Test : Pulsed width $\leq 300 \mu s$, Duty cycle $\leq 2\%$
- Essentially independent of operating temperature



佳恩半导体
JIAENSEMI

JFFC18N65C
JFPC18N65C

Typical Characteristics





佳恩半导体
JIAENSEMI

JFFC18N65C
JFPC18N65C

Figure 5. Capacitance Characteristics

Figure 6. Gate Charge Characteristics

Typical Characteristics

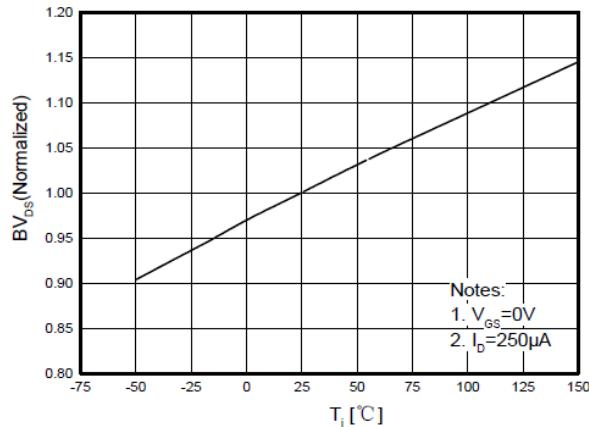


Figure 7. Breakdown Voltage Variation
vs Temperature

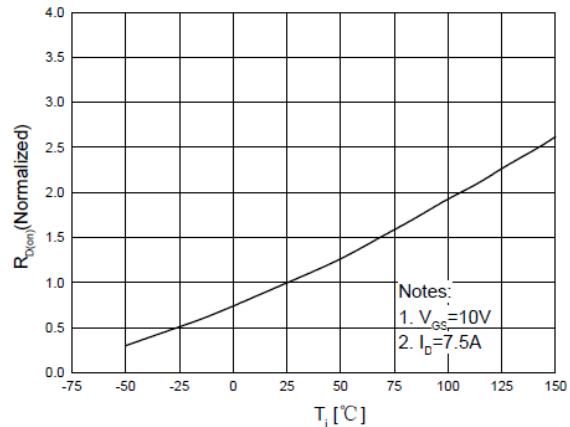


Figure 8. On-Resistance Variation
vs Temperature

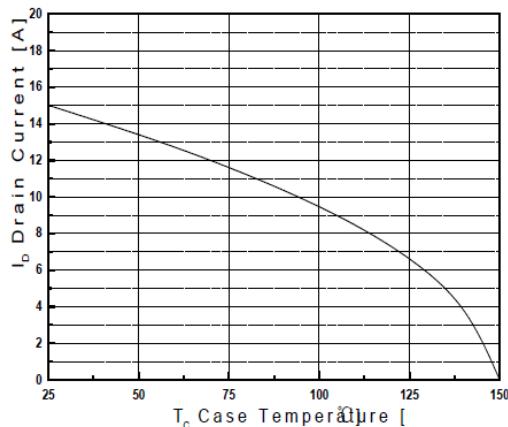


Figure 10. Maximum Drain Current
vs Case Temperature



佳恩半导体
JIAENSEMI

JFFC18N65C
JFPC18N65C

Typical Characteristics

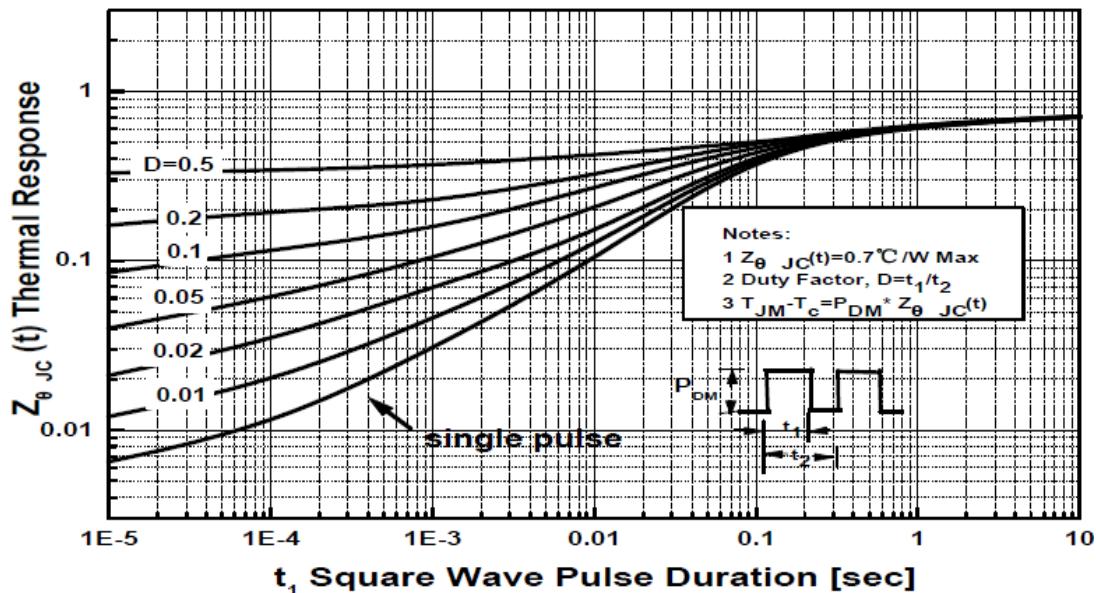


Figure 11-1. Transient Thermal Response Curve for JFPC18N65C

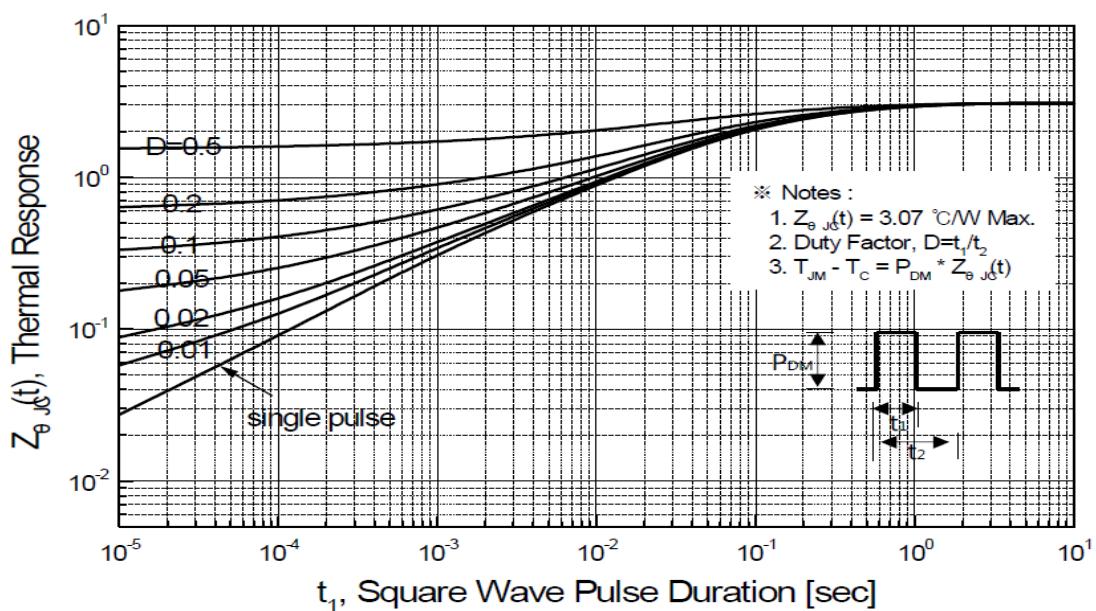


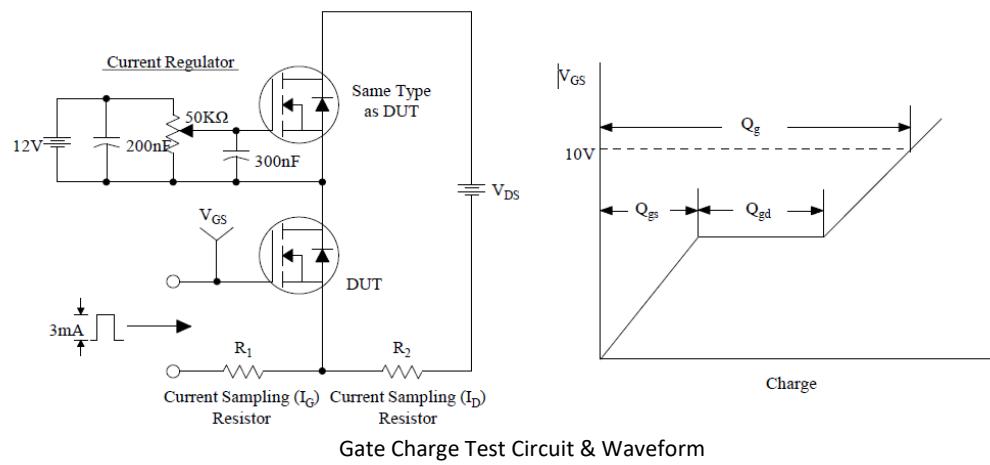
Figure 11-2. Transient Thermal Response Curve for JFFC18N65C



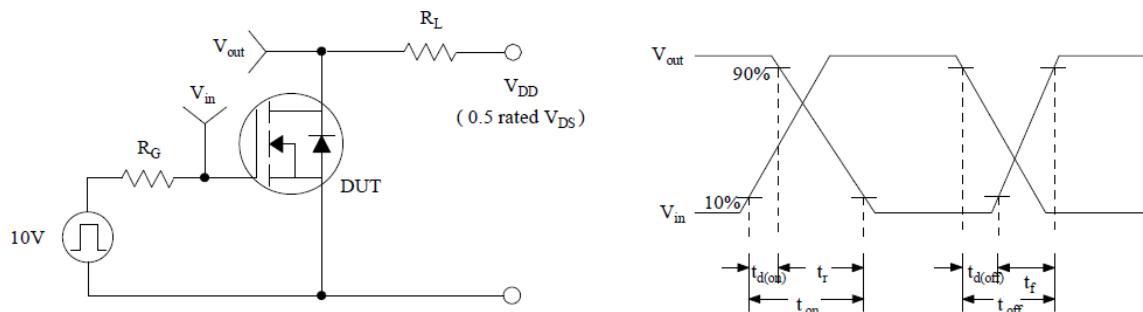
佳恩半导体
JIAENSEMI

JFFC18N65C
JFPC18N65C

Test Circuit & Waveform



Gate Charge Test Circuit & Waveform

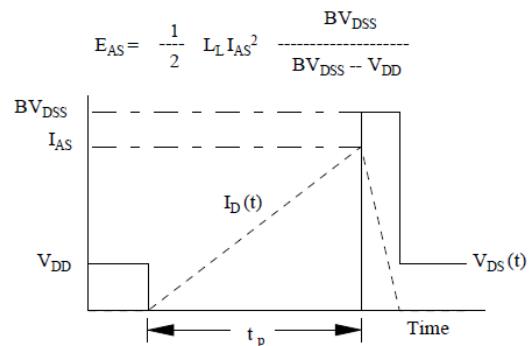
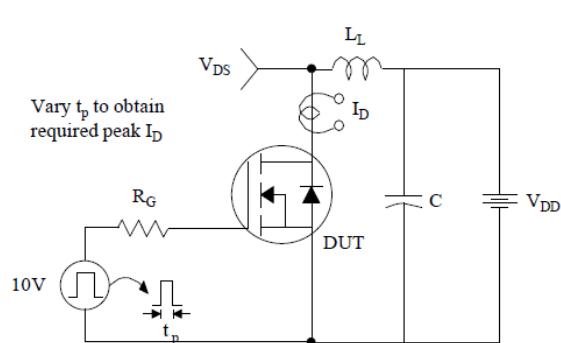


Resistive Switching Test Circuit & Waveforms



佳恩半导体
JIAENSEMI

JFFC18N65C
JFPC18N65C



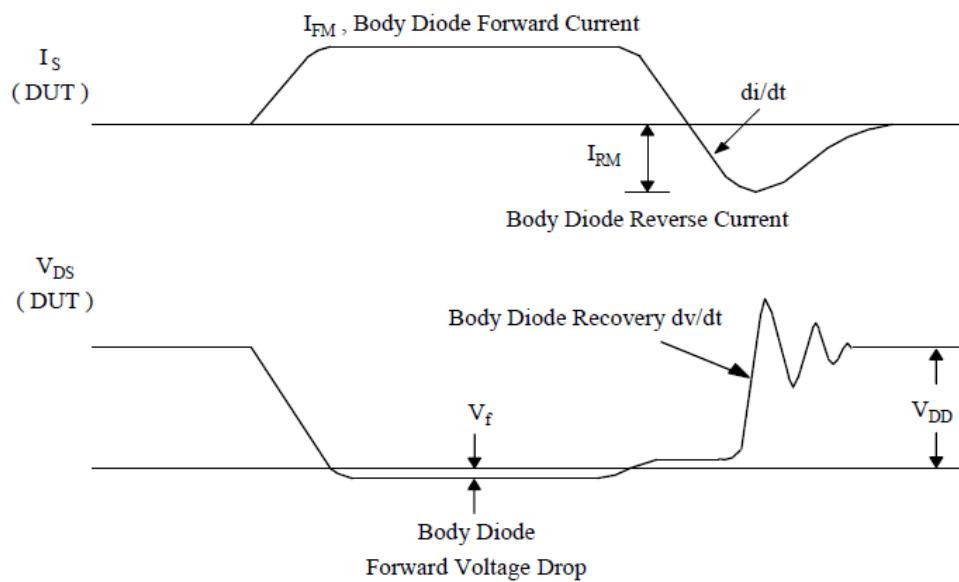
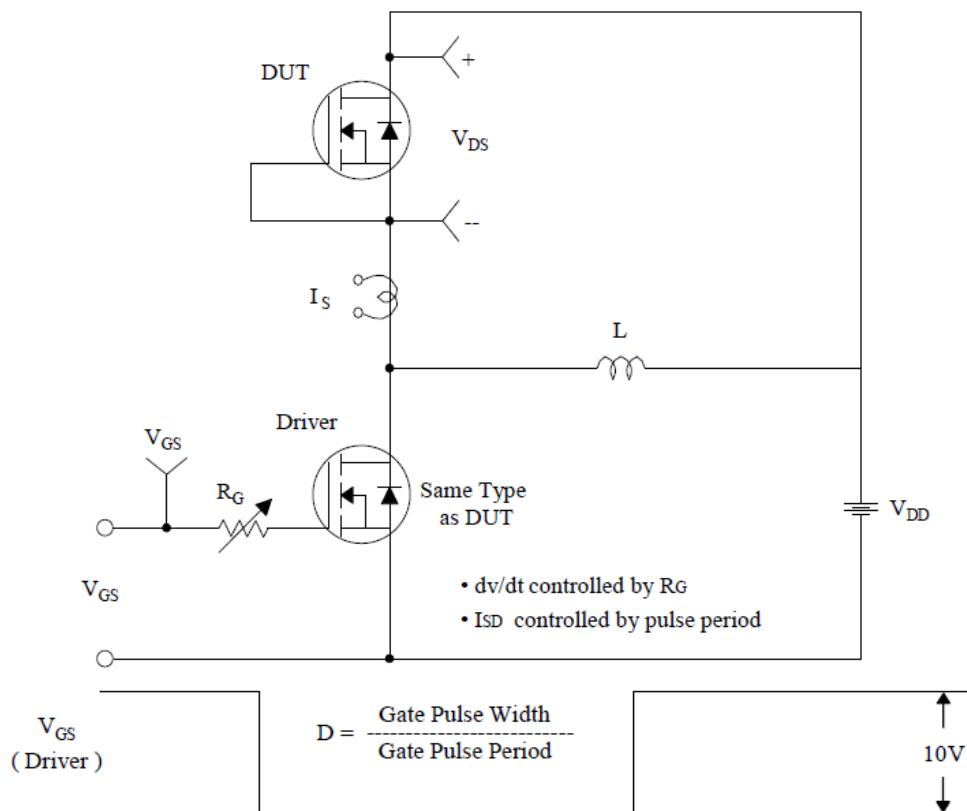
Unclamped Inductive Switching Test Circuit & Waveforms

Test Circuit & Waveform



佳恩半导体
JIAENSEMI

JFFC18N65C
JFPC18N65C



Peak Diode Recovery dv/dt Test Circuit & Waveforms